

Notice of References Cited	Application/Control No. 10/065,878	Applicant(s)/Patent Under Reexamination MILLER ET AL.	
	Examiner Duy M. Dang	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,058,210 B2	06-2006	Mundy et al.	382/128
*	B	US-6,549,649 B1	04-2003	Penkethman, John A.	382/151
*	C	US-2003/0144598 A1	07-2003	Zhang et al.	600/529
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Miller et al. ("MUSE: Robust Surface Fitting using Unbiased Scale Estimates", IEEE 1996, pp: 300-306)
	V	Miller et al. ("Prediction Intervals for Surface Growing Range Segmentation", IEEE 1997, pp: 1027-1033)
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.